

QUADRUPLE 2-INPUT NAND GATE



The HEF4011B provides the positive quadruple 2-input NAND function. The outputs are fully buffered for highest noise immunity and pattern insensitivity of output impedance.

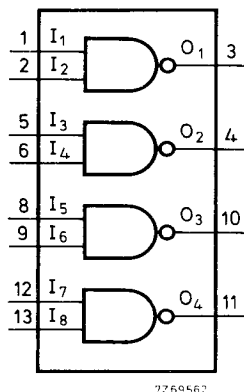


Fig. 1 Functional diagram.

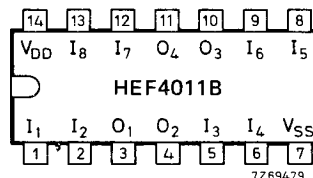


Fig. 2 Pinning diagram.

HEF4011BP : 14-lead DIL; plastic (SOT-27).
HEF4011BD : 14-lead DIL; ceramic (cerdip) (SOT-73).
HEF4011BT : 14-lead mini-pack; plastic (SO-14; SOT-108A).

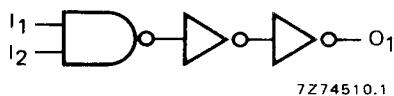


Fig. 3 Logic diagram (one gate).

FAMILY DATA

I_{DD} LIMITS category GATES

see Family Specifications

A.C. CHARACTERISTICS

 $V_{SS} = 0\text{ V}$; $T_{amb} = 25\text{ }^{\circ}\text{C}$; $C_L = 50\text{ pF}$; input transition times $\leq 20\text{ ns}$

	V_{DD} V	symbol	typ	max		typical extrapolation formula
Propagation delays $I_n \rightarrow O_n$	5	$t_{PHL}; t_{PLH}$	55	110	ns	$28\text{ ns} + (0,55\text{ ns/pF}) C_L$
	10		25	45	ns	$14\text{ ns} + (0,23\text{ ns/pF}) C_L$
	15		20	35	ns	$12\text{ ns} + (0,16\text{ ns/pF}) C_L$
Output transition times HIGH to LOW	5	t_{THL}	60	120	ns	$10\text{ ns} + (1,0\text{ ns/pF}) C_L$
	10		30	60	ns	$9\text{ ns} + (0,42\text{ ns/pF}) C_L$
	15		20	40	ns	$6\text{ ns} + (0,28\text{ ns/pF}) C_L$
LOW to HIGH	5	t_{TLH}	60	120	ns	$10\text{ ns} + (1,0\text{ ns/pF}) C_L$
	10		30	60	ns	$9\text{ ns} + (0,42\text{ ns/pF}) C_L$
	15		20	40	ns	$6\text{ ns} + (0,28\text{ ns/pF}) C_L$

	V_{DD} V	typical formula for P (μW)	where f_i = input freq. (MHz) f_o = output freq. (MHz) C_L = load capacitance (pF) $\Sigma(f_o C_L)$ = sum of outputs V_{DD} = supply voltage (V)
Dynamic power dissipation per package (P)	5	$1300 f_i + \Sigma(f_o C_L) \times V_{DD}^2$	
	10	$6000 f_i + \Sigma(f_o C_L) \times V_{DD}^2$	
	15	$20\,100 f_i + \Sigma(f_o C_L) \times V_{DD}^2$	